


<b>Search Notes</b>  	<b>Application/Control No.</b>  10598020	<b>Applicant(s)/Patent Under Reexamination</b>  DAVIES, CHRISTOPHER MICHAEL
	<b>Examiner</b>  WEI ZHAO	<b>Art Unit</b>  2475

SEARCHED			
Class	Subclass	Date	Examiner
370	255	9/8, 2/3/2011	WZ
709	243, 239	9/8, 2/3/2011	WZ
455	566	9/8	WZ

SEARCH NOTES		
Search Notes	Date	Examiner
Searched using US-PGPUB, USPAT, DERWENT, IBM_TDB in EAST	9/8, 2/3/2011	WZ
Did double patenting search and inventorship search for ODP in Palm Resource Center	9/8, 2/3/2011	WZ

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
370	255	9/8, 2/3/2011	WZ

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